The manufacturer may use the mark:



Reports:

YEC 11-10-046 R003 V1R2 Assessment Report YEC 11-10-046 R002 V1R2 FMEDA Report

Validity:

This assessment is valid for the EJA DP and Pressure Transmitter, E Series and J Series.

This assessment is valid until July 1, 2015.

Revision 1.2 August 29, 2012



Certificate / Certificat

Zertifikat / 合格証

YEC 1110046 C001

exida hereby confirms that the:

EJA DP and Pressure Transmitter, E Series and J Series

Yokogawa Electric Corporation Musashino-shi, Tokyo, Japan

Has been assessed per the relevant requirements of:

IEC 61508: 2010 Parts 1-7

and meets requirements providing a level of integrity to:

Systematic Integrity: SIL 3 Capable

Random Integrity: Type B Element

PFD_{AVG} and Architecture Constraints must be verified for each application

Safety Function:

An EJA DP and Pressure Transmitter, E Series and J Series will measure pressure and output a 4-20 mA signal within the stated safety accuracy

Application Restrictions:

The unit must be properly designed into a Safety Instrumented Function per the Safety Manual requirements.



Evaluating Assessor

Driff Francis

Certifying Assessor

Certificate / Certificat / Zertifikat / 合格証

YEC 1110046 C001

Systematic Integrity: SIL 3 Capable

Random Integrity: Type B Element

PFD_{AVG} and Architecture Constraints must be verified for each application

SIL 3 Capability:

The product has met manufacturer design process requirements of Safety Integrity Level (SIL) 3. These are intended to achieve sufficient integrity against systematic errors of design by the manufacturer.

A Safety Instrumented Function (SIF) designed with this product must not be used at a SIL level higher than stated without "prior use" justification by end user or diverse technology redundancy in the design.

IEC 61508 Failure Rates in FIT*

Device	λ_{SD}	λ _{su}	λ_{DD}	λ _{DU}
EJA DP and Pressure Transmitter, E Series	0	54	331	39
and J Series without Remote Seal				

SIL Verification:

The Safety Integrity Level (SIL) of an entire Safety Instrumented Function (SIF) must be verified via a calculation of PFD_{AVG} considering redundant architectures, proof test interval, proof test effectiveness, any automatic diagnostics, average repair time and the specific failure rates of all products included in the SIF. Each subsystem must be checked to assure compliance with minimum hardware fault tolerance (HFT) requirements.

* FIT = 1 failure / 109 hours



Yokogawa Electric Corporation

Musashino-shi, Tokyo, Japan



Form	Version	Date
C61508	2.7-2	Mar 2011